

MITSUBISHI IGBT MODULES  
**CM1000DUC-34NF**  
 HIGH POWER SWITCHING USE  
 INSULATED TYPE

**CM1000DUC-34NF**

- MPD series using 5<sup>th</sup> Generation IGBT and FWDi -



**Dual (Half-Bridge)**

- I<sub>C</sub> ..... 1000 A
- V<sub>CES</sub> ..... 1700 V
- Flat base Type  
Copper (non-plating) base plate
- RoHS Directive compliant

**APPLICATION**

AC Motor Control, Motion/Servo Control, Power supply, etc.

**OUTLINE DRAWING & INTERNAL CONNECTION**

Dimension in mm

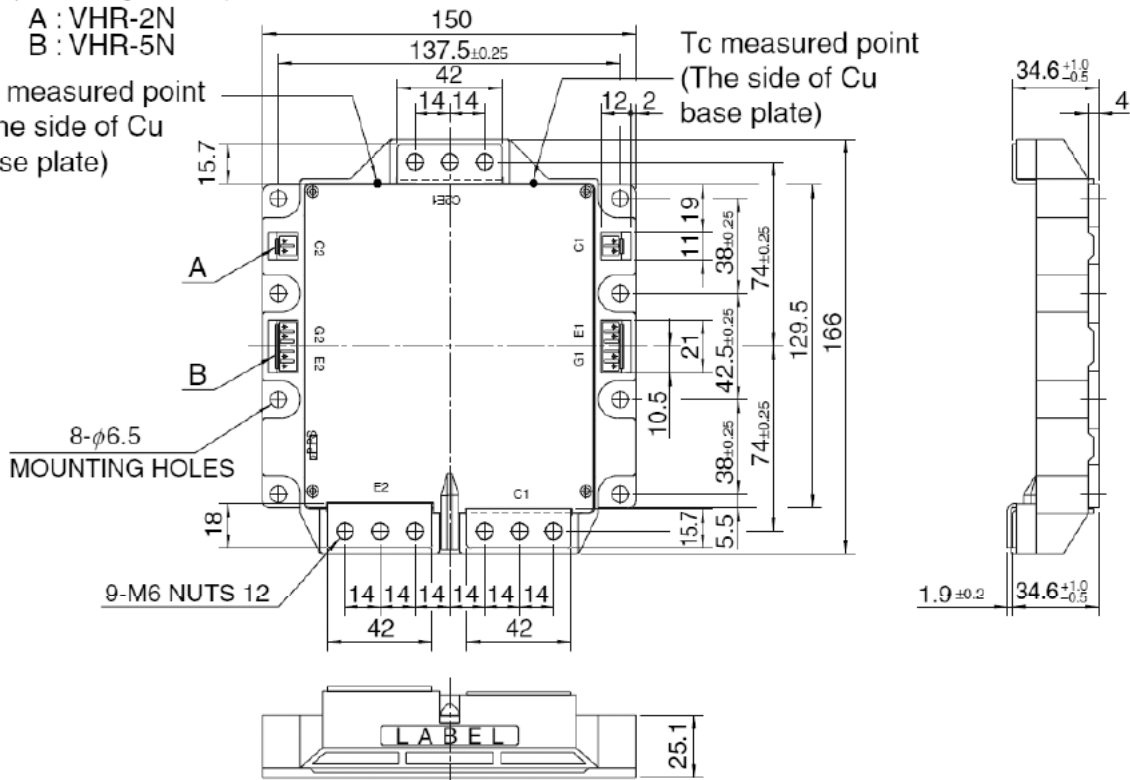
A,B HOUSING Type

(J. S. T. Mfg. Co. Ltd)

A : VHR-2N

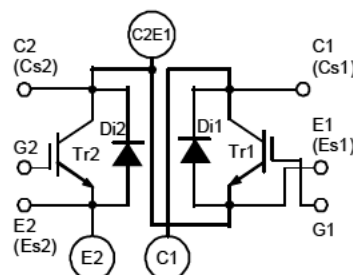
B : VHR-5N

T<sub>c</sub> measured point  
(The side of Cu  
base plate)



**INTERNAL CONNECTION**

Tolerance otherwise specified	
Division of Dimension	Tolerance
0.5 to 3	±0.2
over 3 to 6	±0.3
over 6 to 30	±0.5
over 30 to 120	±0.8
over 120 to 400	±1.2



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**ABSOLUTE MAXIMUM RATINGS (T<sub>j</sub>=25 °C, unless otherwise specified)**

Symbol	Item	Conditions	Rating	Unit
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1700	V
V <sub>GES</sub>	Gate-emitter voltage	C-E short-circuited	±20	V
I <sub>C</sub>	Collector current	DC, T <sub>C</sub> =104 °C (Note.2)	1000	A
I <sub>CRM</sub>		Pulse, Repetitive (Note.3)	2000	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note.2, 4)	8925	W
I <sub>E</sub> (Note.1)	Emitter current (Free wheeling diode forward current)	T <sub>C</sub> =25 °C (Note.2, 4)	1000	A
I <sub>ERM</sub> (Note.1)		Pulse, Repetitive (Note.3)	2000	
T <sub>j</sub>	Junction temperature	-	-40 ~ +150	°C
T <sub>stg</sub>	Storage temperature	(Note.7)	-40 ~ +125	
V <sub>isol</sub>	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	3500	V

**ELECTRICAL CHARACTERISTICS (T<sub>j</sub>=25 °C, unless otherwise specified)**

Symbol	Item	Conditions	Limits			Unit	
			Min.	Typ.	Max.		
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited	-	-	1	mA	
I <sub>GES</sub>	Gate-emitter leakage current	±V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited	-	-	5	µA	
V <sub>GE(th)</sub>	Gate-emitter threshold voltage	I <sub>C</sub> =100 mA, V <sub>CE</sub> =10 V	6	7	8	V	
V <sub>CEsat</sub>	Collector-emitter saturation voltage	I <sub>C</sub> =1000 A (Note.5), V <sub>GE</sub> =15 V	T <sub>j</sub> =25 °C	-	2.2	2.85	V
			T <sub>j</sub> =125 °C	-	2.45	-	
C <sub>ies</sub>	Input capacitance	V <sub>CE</sub> =10 V, G-E short-circuited	-	-	220	nF	
C <sub>oes</sub>	Output capacitance		-	-	25		
C <sub>res</sub>	Reverse transfer capacitance		-	-	4.7		
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =1000 V, I <sub>C</sub> =1000 A, V <sub>GE</sub> =15 V	-	6000	-	nC	
t <sub>d(on)</sub>	Turn-on delay time	V <sub>CC</sub> =1000 V, I <sub>C</sub> =1000 A, V <sub>GE</sub> =±15 V, R <sub>G</sub> =0.47 Ω, Inductive load	-	-	600	ns	
t <sub>r</sub>	Rise time		-	-	200		
t <sub>d(off)</sub>	Turn-off delay time		-	-	1000		
t <sub>f</sub>	Fall time		-	-	300		
V <sub>EC</sub> (Note.1)	Emitter-collector voltage	I <sub>E</sub> =1000 A (Note.5), G-E short-circuited	-	2.3	3.0	V	
t <sub>rr</sub> (Note.1)	Reverse recovery time	V <sub>CC</sub> =1000 V, I <sub>E</sub> =1000 A, V <sub>GE</sub> =±15 V, R <sub>G</sub> =0.47 Ω, Inductive load	-	-	500	ns	
Q <sub>rr</sub> (Note.1)	Reverse recovery charge	R <sub>G</sub> =0.47 Ω, Inductive load	-	90	-	µC	
E <sub>on</sub>	Turn-on switching energy per pulse	V <sub>CC</sub> =1000 V, I <sub>C</sub> =I <sub>E</sub> =1000 A, V <sub>GE</sub> =±15 V, R <sub>G</sub> =0.47 Ω, T <sub>j</sub> =125 °C, Inductive load	-	272.4	-	mJ	
E <sub>off</sub>	Turn-off switching energy per pulse		-	250.2	-		
E <sub>rr</sub> (Note.1)	Reverse recovery energy per pulse		-	172.4	-		
R <sub>CC+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25 °C (Note.2)	-	0.286	-	mΩ	
r <sub>g</sub>	Internal gate resistance	Per switch	-	0.67	-	Ω	

**THERMAL RESISTANCE CHARACTERISTICS**

Symbol	Item	Conditions	Limits			Unit
			Min.	Typ.	Max.	
R <sub>th(j-c)Q</sub>	Thermal resistance (Note.2)	Junction to case, per IGBT	-	-	14	K/KW
R <sub>th(j-c)D</sub>		Junction to case, per FWDi	-	-	23	K/KW
R <sub>th(c-s)</sub>	Contact thermal resistance (Note.2)	Case to heat sink, per 1/2 module, Thermal grease applied (Note.8)	-	12	-	K/KW

**MECHANICAL CHARACTERISTICS**

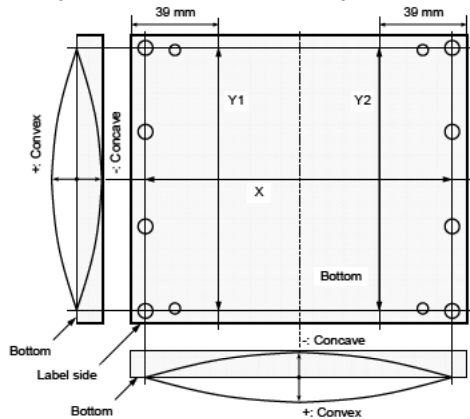
Symbol	Item	Conditions	Limits			Unit
			Min.	Typ.	Max.	
M <sub>t</sub>	Mounting torque	Main terminals M 6 screw	3.5	4.0	4.5	N·m
M <sub>s</sub>		Mounting to heat sink M 6 screw	3.5	4.0	4.5	
m	Weight	-	-	1450	-	g
e <sub>c</sub>	Flatness of base plate	On the centerline X, Y1, Y2 (Note.8)	-50	-	+100	µm

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**RECOMMENDED OPERATING CONDITIONS ( $T_a=25\text{ }^\circ\text{C}$ )**

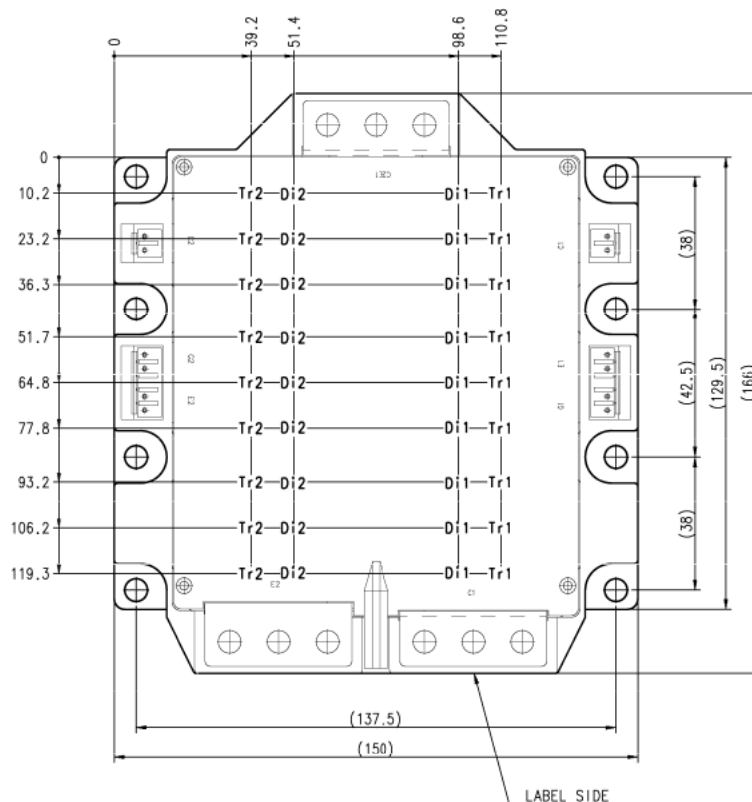
Symbol	Item	Conditions	Limits			Unit
			Min.	Typ.	Max.	
$V_{CC}$	(DC) Supply voltage	Applied across C1-E2	-	1000	1100	V
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2	13.5	15.0	16.5	
$R_G$	External gate resistance	Per switch	0.47	-	4.7	$\Omega$

- Note.1: Represent ratings and characteristics of the anti-parallel, emitter-collector free wheeling diode (FWDi).  
Note.2: Case temperature ( $T_c$ ) and heat sink temperature ( $T_s$ ) are defined on the each surface of base plate and heat sink just under the chips. (Refer to the figure of chip location)  
The heat sink thermal resistance  $\{R_{th(s-a)}\}$  should measure just under the chips.  
Note.3: Pulse width and repetition rate should be such that the device junction temperature ( $T_j$ ) dose not exceed  $T_{jmax}$  rating.  
Note.4: Junction temperature ( $T_j$ ) should not increase beyond  $T_{jmax}$  rating.  
Note.5: Pulse width and repetition rate should be such as to cause negligible temperature rise.  
(Refer to the figure of test circuit)  
Note.6: Typical value is measured by using thermally conductive grease of  $\lambda=0.9\text{ W/(m}\cdot\text{K)}$ .  
Note.7: The operation temperature is restrained by the permission temperature of female connector housing.  
Note.8: Base plate flatness measurement points are as in the following figure.



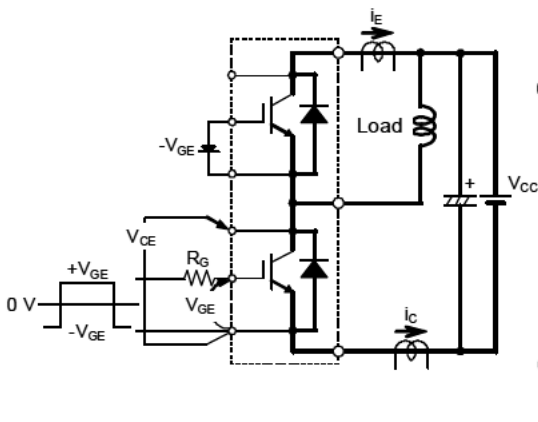
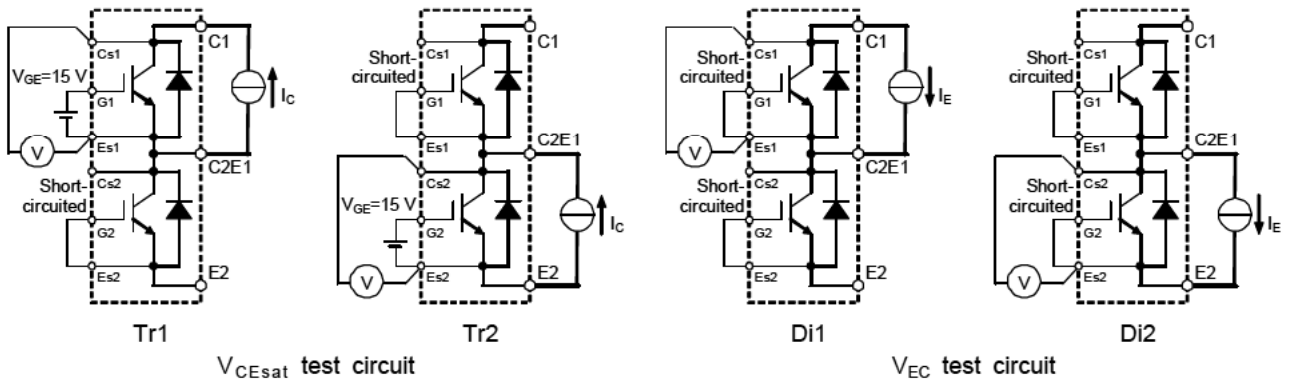
**CHIP LOCATION (Top view)**

Dimension in mm, tolerance:  $\pm 1\text{ mm}$

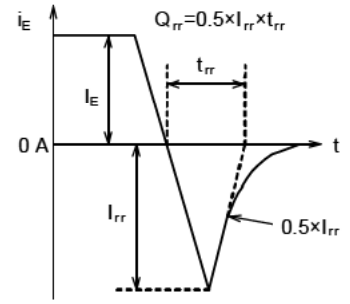
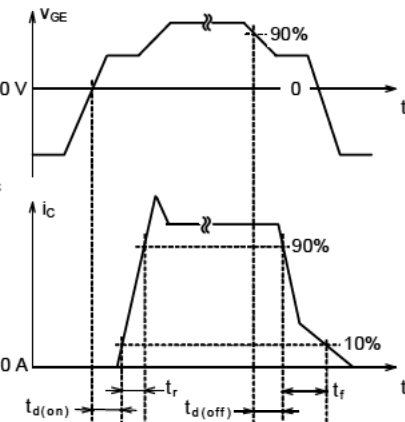


Tr1/Tr2: IGBT, Di1/Di2: FWDi. Each mark points the center position of each chip.

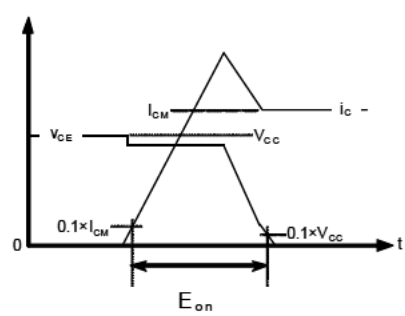
**TEST CIRCUIT AND WAVEFORMS**



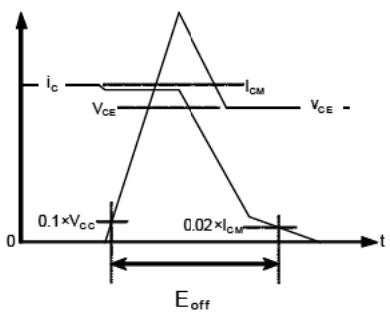
Switching characteristics test circuit and waveforms



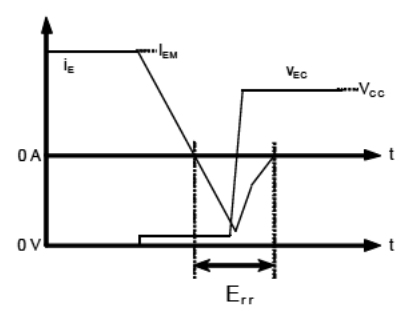
$t_{rr}$ ,  $Q_{rr}$  test waveform



IGBT Turn-on switching energy



IGBT Turn-off switching energy

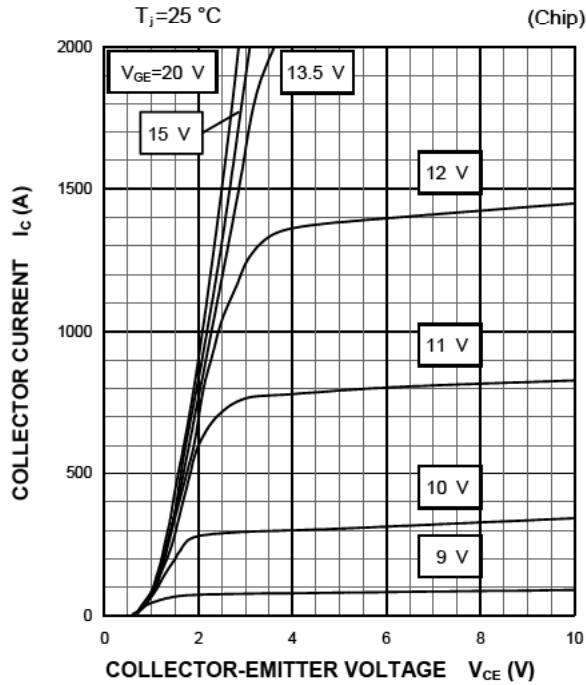


FWDi Reverse recovery energy

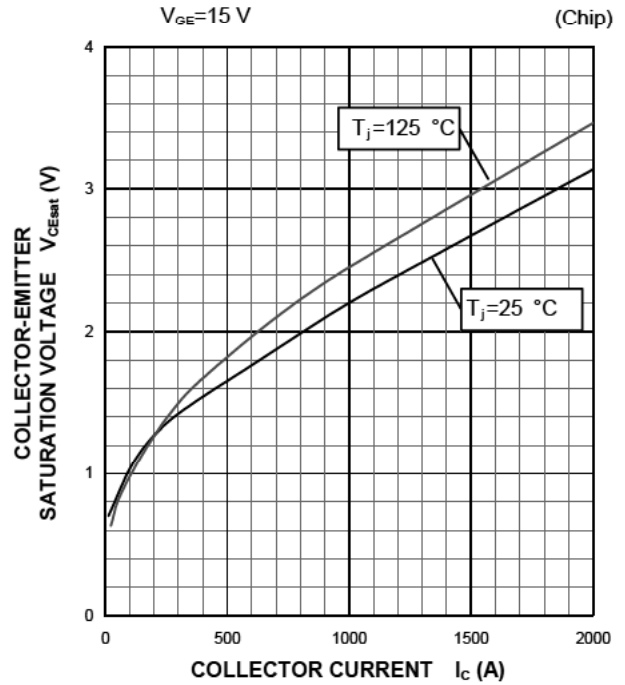
Turn-on / Turn-off switching energy and Reverse recovery energy integral range

PERFORMANCE CURVES

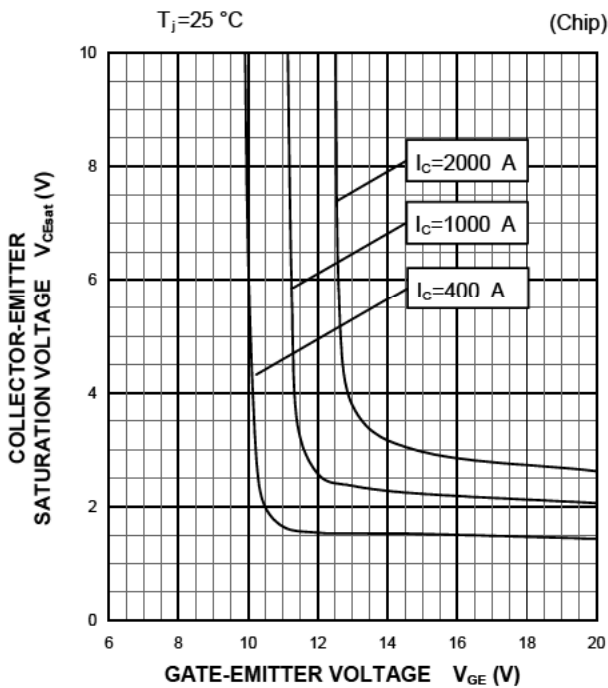
OUTPUT CHARACTERISTICS  
 (TYPICAL)



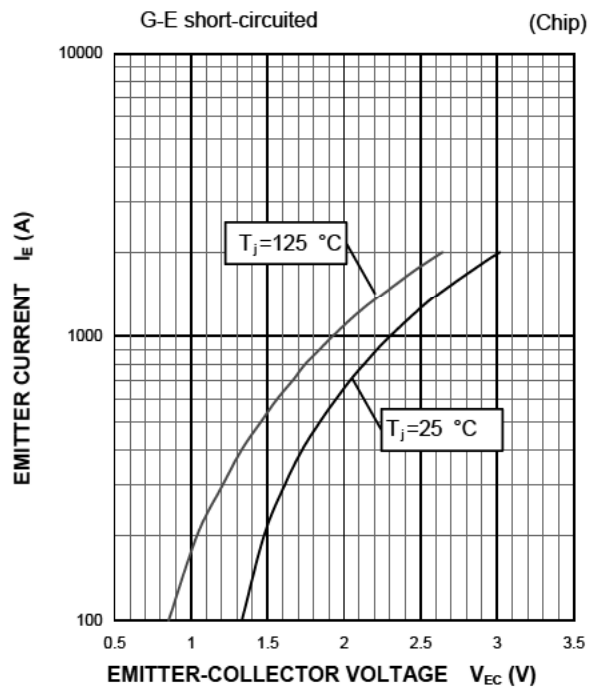
COLLECTOR-EMITTER SATURATION  
 VOLTAGE CHARACTERISTICS  
 (TYPICAL)



COLLECTOR-EMITTER SATURATION  
 VOLTAGE CHARACTERISTICS  
 (TYPICAL)



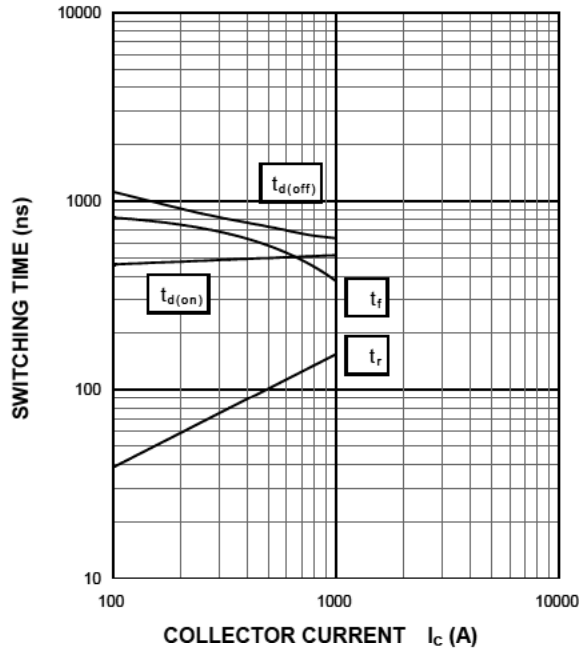
FREE WHEELING DIODE  
 FORWARD CHARACTERISTICS  
 (TYPICAL)



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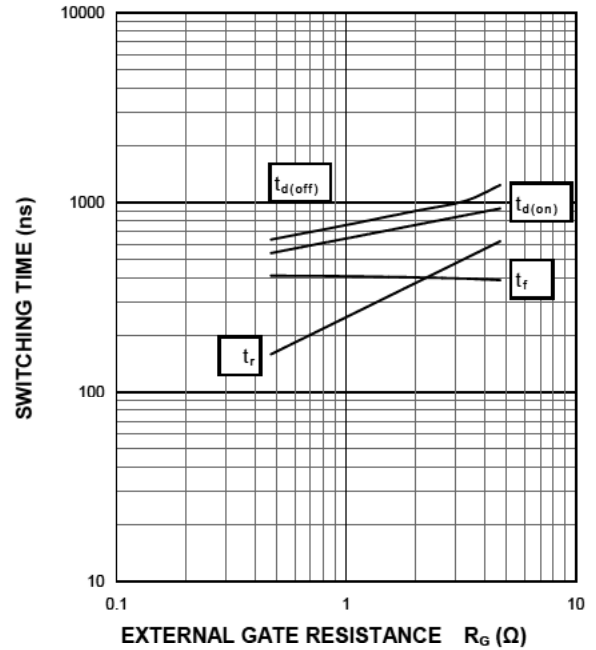
HALF-BRIDGE  
 SWITCHING CHARACTERISTICS  
 (TYPICAL)

$V_{CC}=1000\text{ V}$ ,  $V_{GE}=\pm 15\text{ V}$ ,  $R_G=0.47\ \Omega$ ,  $T_j=125\text{ }^\circ\text{C}$ ,  
 INDUCTIVE LOAD



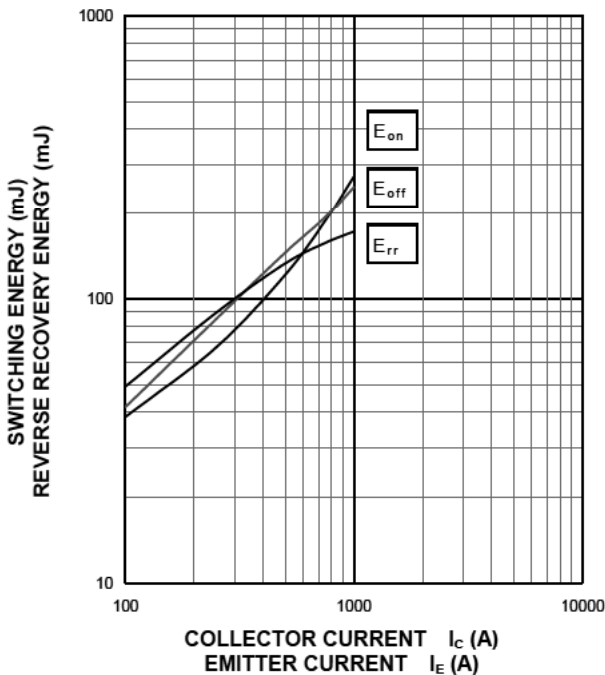
HALF-BRIDGE  
 SWITCHING CHARACTERISTICS  
 (TYPICAL)

$V_{CC}=1000\text{ V}$ ,  $I_c=1000\text{ A}$ ,  $V_{GE}=\pm 15\text{ V}$ ,  $T_j=125\text{ }^\circ\text{C}$ ,  
 INDUCTIVE LOAD



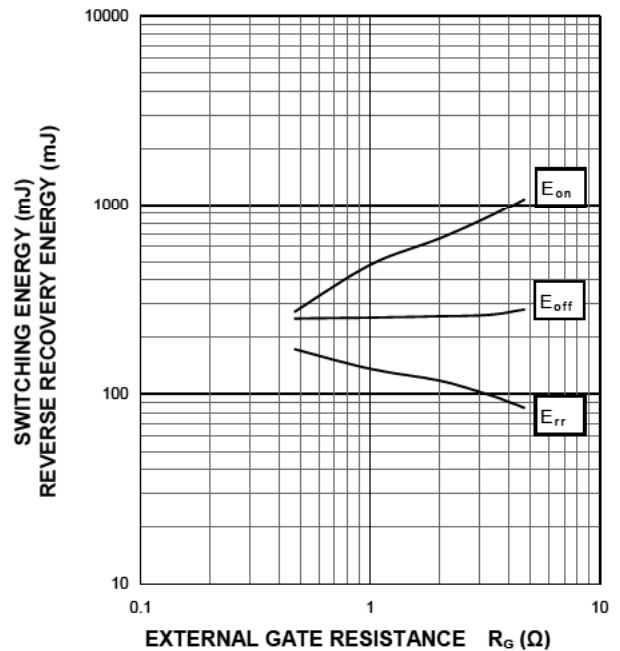
HALF-BRIDGE  
 SWITCHING CHARACTERISTICS  
 (TYPICAL)

$V_{CC}=1000\text{ V}$ ,  $V_{GE}=\pm 15\text{ V}$ ,  $R_G=0.47\ \Omega$ ,  $T_j=125\text{ }^\circ\text{C}$ ,  
 INDUCTIVE LOAD, PER PULSE



HALF-BRIDGE  
 SWITCHING CHARACTERISTICS  
 (TYPICAL)

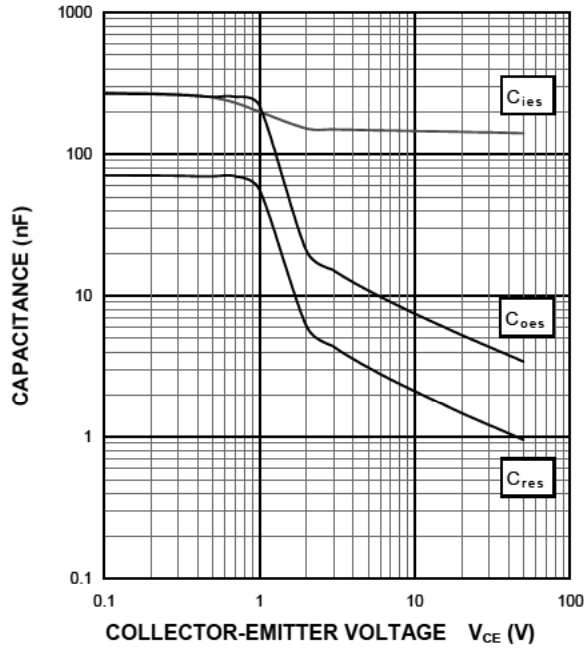
$V_{CC}=1000\text{ V}$ ,  $I_c/I_E=1000\text{ A}$ ,  $V_{GE}=\pm 15\text{ V}$ ,  $T_j=125\text{ }^\circ\text{C}$ ,  
 INDUCTIVE LOAD, PER PULSE



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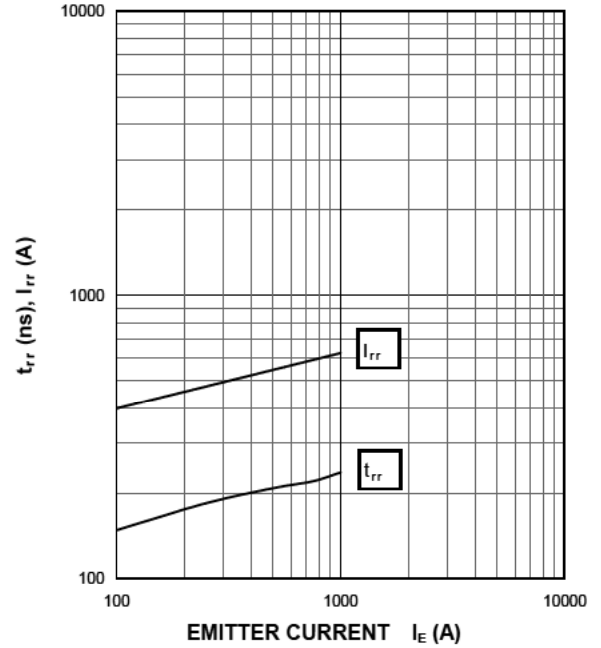
**CAPACITANCE CHARACTERISTICS  
 (TYPICAL)**

G-E short-circuited,  $T_j=25\text{ }^\circ\text{C}$



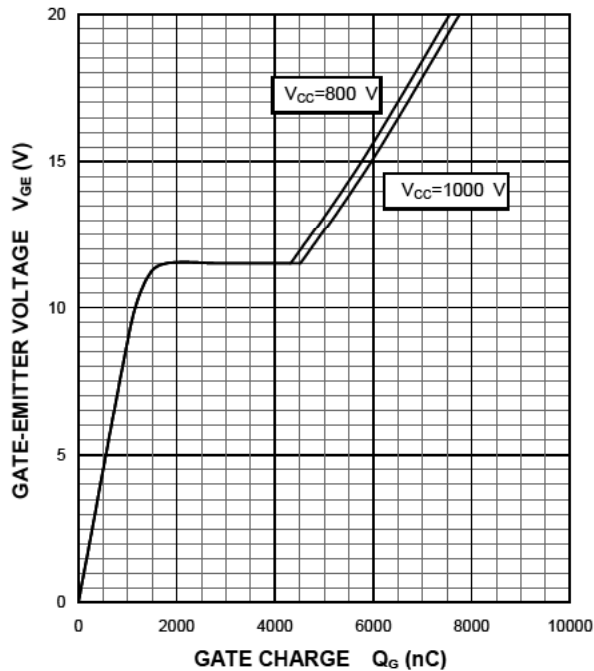
**FREE WHEELING DIODE  
 REVERSE RECOVERY CHARACTERISTICS  
 (TYPICAL)**

$V_{CC}=1000\text{ V}$ ,  $V_{GE}=\pm 15\text{ V}$ ,  $R_G=0.47\ \Omega$ ,  $T_j=25\text{ }^\circ\text{C}$ ,  
 INDUCTIVE LOAD



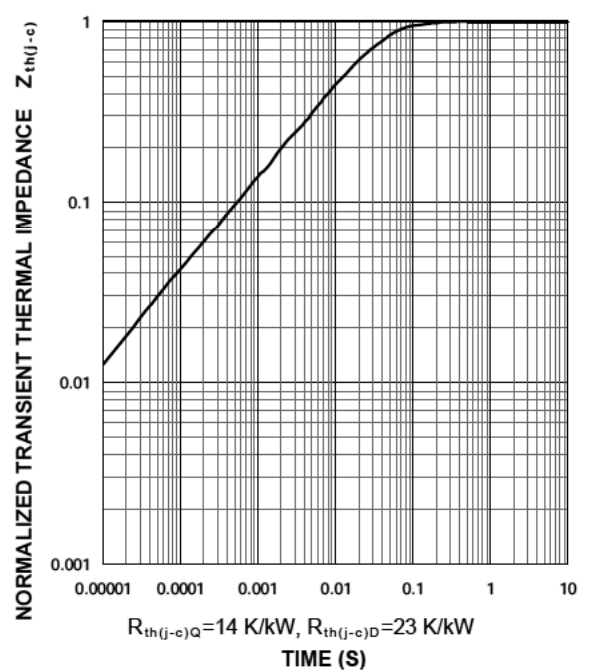
**GATE CHARGE CHARACTERISTICS  
 (TYPICAL)**

$I_c=1000\text{ A}$ ,  $T_j=25\text{ }^\circ\text{C}$



**TRANSIENT THERMAL IMPEDANCE  
 CHARACTERISTICS  
 (MAXIMUM)**

Single pulse,  $T_c=25\text{ }^\circ\text{C}$



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